

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/911,596	UENOYAMA ET AL.	
Examiner	Art Unit	
Allen Wong	2613	

	SEARCHED				
Class	Subclass	Date	Examiner		
375	240	1/19/2006	AW		
375	240.01	1/19/2006	AW		
375	240.12	1/19/2006	AW		
375	240.16	1/19/2006	AW		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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